

SCANtek⁵

Maximum Productivity



Advanced 5-axis multi-sensor technology for unrivalled performance

Ten times more productive than its closest rival, LK Metrology's SCANtek5 technology has boosted measurement throughput, shortened production lead times and provided a complete dimensional insight for manufacturers of precision parts and series production.

REVO[®] and MODUSTM trademarks of Renishaw plc.

Contact us to book your demonstration

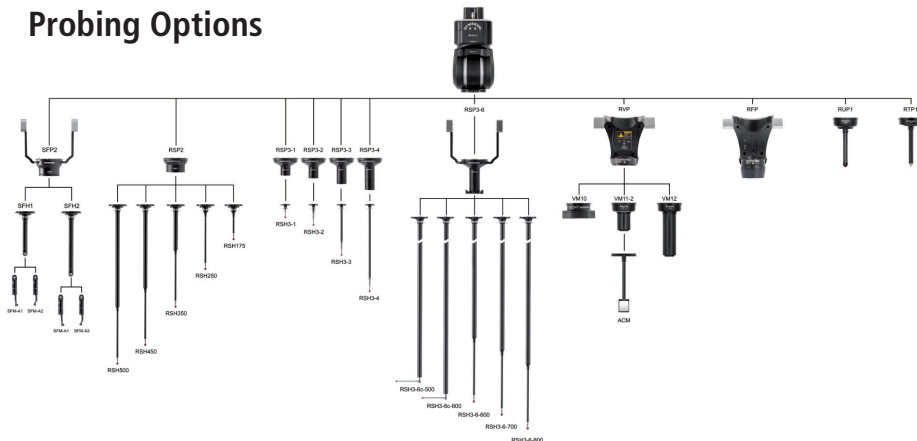
www.LKmetrology.com

scantek⁵

Unprecedented measuring speed, the flexibility of multi-sensor technology and optimized 5-axis metrology have boosted measurement throughput, shortened production lead times and provided a more complete awareness of product conformance.

Combining the benefits of ceramic CMM technology and the most advanced 5-axis multi-sensor system, ALTERA SCANTek provides five interchangeable probe technologies, including tactile scanning, touch-trigger, surface finish, non-contact vision and ultrasonic probes to enable automated selection of the most advantageous probing technology while maximizing the advantages of 5-axis measurement, infinite probe head positioning and long probe assemblies.

Probing Options



Model Sizes

ALTERA^M

8.7.6	10.10.8	15.12.10	20.15.10	20.15.12	20.15.15	25.20.15
10.7.6	15.10.8	20.12.10	25.15.10	25.15.12	25.15.15	30.20.15
	20.10.8	25.12.10	30.15.10	30.15.12	30.15.15	35.20.15
	25.10.8	30.12.10	35.15.10	35.15.12	35.15.15	40.20.15
					40.15.15	50.20.15
						60.20.15

(Measure volume = xxx00mm)

ALTERA^{SL}

8.7.6	10.10.8	15.12.10	25.15.10	20.15.15	25.20.15
10.7.6	15.10.8	20.12.10		25.15.15	
15.7.6	20.10.8	25.12.10			

(Measure volume = xxx00mm)

Performance

ALTERA^M

ALTERA^{SL}

Volumetric Accuracy	from 1.4 µm +L/375	from 1.5 µm +L/400
Repeatability	from 1.4 µm	from 0.7 µm
Probing Accuracy	from 1.2 µm	from 0.9 µm
Scanning Accuracy	from 3,0 µm / 90s	from 3,0 µm / 48s
Velocity	from 830 mm/s	from 850 mm/s
Acceleration	from 2,510 mm/s ²	from 1,400 mm/s ²



LK Metrology's ceramic technology CMM is guaranteed to maintain its original specification for a period of 10 years*

*Conditions apply, see LK Metrology website for full details.



Multi-sensor Inspection

High performance scanning, non-contact inspection and surface finish analysis on a single CMM.



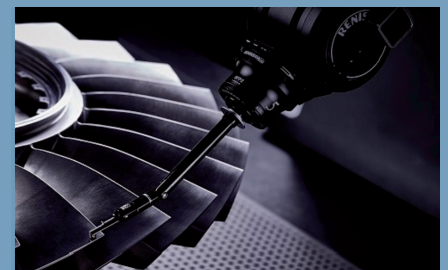
Ultra Fast Scanning

SCANTek technology allows the stylus to follow a continuous path around complex components without leaving the surface.



Non-contact Inspection

Measure small and delicate features unsuitable for tactile measurement. Two vision modules provide inspection capability for different applications.



Surface Finish Analysis

Combine surface finish analysis with other CMM measurements in a single operation.